



AD7492

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Fax: 781/326-8703 Analog Devices, Inc., 1998

AD7492—SPECIFICATIONS¹ ($V_{DD} = +2.7\text{ V}$ to $+5.25\text{ V}$ ⁴, $T_A = T_{MIN}$ to T_{MAX} ⁵, unless otherwise noted.)

Parameter	A Version ¹		Units	Test Conditions/Comments
DYNAMIC PERFORMANCE	5 V	3 V		$f_s = 1\text{ MSPS @ } 5\text{ V}$, $f_s = 1\text{ MSPS @ } 3\text{ V}$
Signal to Noise + Distortion (SINAD)	69	69	dB typ	$f_{IN} = 500\text{ kHz}$ Sine Wave
	68	68	dB min	$f_{IN} = 100\text{ kHz}$ Sine Wave
Signal-to-Noise Ratio (SNR)	70	70	dB typ	$f_{IN} = 500\text{ kHz}$ Sine Wave
	68	68	dB min	$f_{IN} = 100\text{ kHz}$ Sine Wave
Total Harmonic Distortion (THD)	-83	-83	dB typ	$f_{IN} = 500\text{ kHz}$ Sine Wave
	-83	-84	dB typ	$f_{IN} = 100\text{ kHz}$ Sine Wave
	-75	-75	dB max	$f_{IN} = 100\text{ kHz}$ Sine Wave
Peak Harmonic or Spurious Noise (SFDR)	-86	-81	dB typ	$f_{IN} = 500\text{ kHz}$ Sine Wave
	-86	-86	dB typ	$f_{IN} = 100\text{ kHz}$ Sine Wave
	-76	-76	dB max	$f_{IN} = 100\text{ kHz}$ Sine Wave
Intermodulation Distortion (IMD)				
Second Order Terms	-77	-77	dB typ	$f_{IN} = 500\text{ kHz}$ Sine Wave
	-86	-86	dB typ	$f_{IN} = 100\text{ kHz}$ Sine Wave
Third Order Terms	-77	-77	dB typ	$f_{IN} = 500\text{ kHz}$ Sine Wave
	-86	-86	dB typ	$f_{IN} = 100\text{ kHz}$ Sine Wave
Aperture Delay	5	5	ns typ	
Aperture Jitter	15	15	ps typ	
Full Power Bandwidth	10	10	MHz typ	
DC ACCURACY				$f_s = 1\text{ MSPS @ } 5\text{ V}$; $f_s = 1\text{ MSPS @ } 3\text{ V}$
Resolution	12	12	Bits	
Integral Nonlinearity	± 1	± 1	LSB max	
Differential Nonlinearity	± 0.9	± 0.9	LSB max	Guaranteed No Missed Codes to 12 Bits
Offset Error	± 10	± 10	LSB max	
Gain Error	± 2	± 2	LSB max	
ANALOG INPUT				
Input Voltage Ranges	0 to 2.5 V	0 to 2.5 V	V	
DC Leakage Current	± 1	± 1	$\mu\text{A max}$	
Input Capacitance	33	33	pF typ	
REFERENCE OUTPUT				
REF OUT Output Voltage Range	2.5	2.5	V	$\pm 1\%$ for Specified Performance
LOGIC INPUTS				
Input High Voltage, V_{INH}	$V_{DRIVE}/2 + 0.4$	$V_{DRIVE}/2 + 0.4$	V min	$V_{DD} = 5\text{ V} \pm 5\%$
Input Low Voltage, V_{INL}	$V_{DRIVE}/2 - 0.4$	$V_{DRIVE}/2 - 0.4$	V max	$V_{DD} = 5\text{ V} \pm 5\%$
Input Current, I_{IN}	± 1	± 1	$\mu\text{A max}$	Typically 10 nA, $V_{IN} = 0\text{ V}$ or V_{DD}
Input Capacitance, C_{IN} ⁴	10	10	pF max	
LOGIC OUTPUTS				
Output High Voltage, V_{OH}	$V_{DRIVE} - 0.2$	$V_{DRIVE} - 0.2$	V min	$I_{SOURCE} = 200\text{ }\mu\text{A}$
Output Low Voltage, V_{OL}	0.4	0.4	V max	$I_{SINK} = 200\text{ }\mu\text{A}$
Floating-State Leakage Current	± 10	± 10	$\mu\text{A max}$	$V_{DD} = 2.7\text{ V}$ to 5.25 V
Floating-State Output Capacitance	10	10	pF max	
Output Coding	Straight (Natural) Binary			
CONVERSION RATE				
Conversion Time	14	14	Clock Cycles (max)	
Track/Hold Acquisition Time	140	140	ns min	
Throughput Rate	1	1	MSPS max	Conversion Time + Acquisition Time
POWER REQUIREMENTS				
V_{DD}	$+2.7/+5.25$		V min/max	
I_{DD} ⁵				Digital I/Ps = 0 V or DV_{DD}
Normal Mode	2.4		mA max	$V_{DD} = 4.75\text{ V}$ to 5.25 V ; $f_s = 1\text{ MSPS}$; Typ 2 mA
Quiescent Current	900		$\mu\text{A max}$	$V_{DD} = 4.75\text{ V}$ to 5.25 V
Normal Mode	1.5		mA max	$V_{DD} = 2.7\text{ V}$ to 3.3 V ; $f_s = 1\text{ MSPS}$; Typ 1.3 mA
Quiescent Current	800		$\mu\text{A max}$	$V_{DD} = 2.7\text{ V}$ to 3.3 V
Partial Sleep Mode			$\mu\text{A max}$	$V_{DD} = 4.75\text{ V}$ to 5.25 V ; $f_s = 500\text{ KSPS}$
Partial Sleep Mode	190		$\mu\text{A max}$	Static
Full Sleep Mode			$\mu\text{A typ}$	$V_{DD} = 4.75\text{ V}$ to 5.25 V ; $f_s = 1\text{ KSPS}$
Full Sleep Mode	1		$\mu\text{A max}$	Static
Power Dissipation ⁵				Digital I/Ps = 0 V or DV_{DD}
Normal Mode	12		mW max	$V_{DD} = 5\text{ V}$
	4.5		mW max	$V_{DD} = 3\text{ V}$
Partial Sleep Mode	tbd		$\mu\text{W max}$	$V_{DD} = 5\text{ V}$
	tbd		$\mu\text{W max}$	$V_{DD} = 3\text{ V}$
Full Sleep Mode	5		$\mu\text{W max}$	$V_{DD} = 5\text{ V}$
	3		$\mu\text{W max}$	$V_{DD} = 3\text{ V}$

NOTES

¹Temperature ranges as follows: A Version: -40°C to $+85^\circ\text{C}$.

⁴Sample tested @ $+25^\circ\text{C}$ to ensure compliance.

⁵See Power vs. Throughput Rate section.

Specifications subject to change without notice.

TIMING SPECIFICATIONS¹ ($V_{DD} = +2.7\text{ V}$ to $+5.25\text{ V}$, $T_A = T_{MIN}$ to T_{MAX} , unless otherwise noted.)

Parameter	Limit at T_{MIN} , T_{MAX} AD7492	Units	Description
$t_{CONVERT}$	810	ns max	Partial Sleep Wake-Up Time
t_{WAKEUP}	1	μs max	Full Sleep Wake-Up Time
	500	μs max	$\overline{CONVST}$ Pulsewidth
t_1	10	ns min	$\overline{CONVST}$ to BUSY Delay, $V_{DD} = 5\text{ V}$
t_2^2	10	ns max	$\overline{CONVST}$ to BUSY Delay, $V_{DD} = 3\text{ V}$
	30	ns max	BUSY to $\overline{CS}$ Setup Time
t_3	0	ns max	$\overline{CS}$ to $\overline{RD}$ Setup Time
t_4^3	0	ns max	$\overline{RD}$ Pulsewidth
t_5	20	ns min	Data Access Time After Falling Edge of $\overline{RD}$
t_6^3	15	ns min	Bus Relinquish Time After Rising Edge of $\overline{RD}$
t_7^4	8	ns max	$\overline{CS}$ to $\overline{RD}$ Hold Time
t_8	0	ns max	Acquisition Time
t_9	140	ns min	Quiet Time
t_{10}	100	ns min	

NOTES

¹Sample tested at $+25^\circ\text{C}$ to ensure compliance. All input signals are specified with $t_r = t_f = 5\text{ ns}$ (10% to 90% of V_{DD}) and timed from a voltage level of 1.6 V . See Figure 1.

² t_2 is 35 ns max @ $+125^\circ\text{C}$.

³Measured with the load circuit of Figure 1 and defined as the time required for the output to cross 0.8 V or 2.0 V.

⁴ t_7 is derived from the measured time taken by the data outputs to change 0.5 V when loaded with the circuit of Figure 1. The measured number is then extrapolated back to remove the effects of charging or discharging the 50 pF capacitor. This means that the time, t_7 , quoted in the timing characteristics is the true bus relinquish time of the part and is independent of the bus loading.

Specifications subject to change without notice.

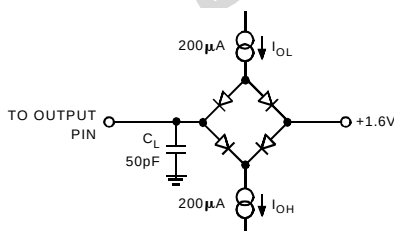


Figure 1. Load Circuit for Digital Output Timing Specifications

ABSOLUTE MAXIMUM RATINGS¹(T_A = +25°C unless otherwise noted)

AV _{DD} to AGND/DGND	-0.3 V to +7 V
DV _{DD} to AGND/DGND	-0.3 V to +7 V
V _{DRIVE} to AGND/DGND	-0.3 V to +7 V
AV _{DD} to DV _{DD}	-0.3 V to +0.3 V
V _{DRIVE} to DV _{DD}	-0.3 V to DV _{DD} + 0.3 V
AGND TO DGND	-0.3 V to +0.3 V
Analog Input Voltage to AGND-0.3 V to AV _{DD} + 0.3 V	
Digital Input Voltage to DGND	-0.3 V to DV _{DD} + 0.3 V
REF IN to AGND	-0.3 V to AV _{DD} + 0.3 V
Input Current to Any Pin Except Supplies ²	±10 mA
Operating Temperature Range	
Commercial (A and B Version)	-40°C to +85°C
Storage Temperature Range	-65°C to +150°C
Junction Temperature	+150°C
SOIC, TSSOP Package Dissipation	+450 mW
θ _{JA} Thermal Impedance	75°C/W (SOIC)
	115°C/W (TSSOP)
θ _{JC} Thermal Impedance	25°C/W (SOIC)
	35°C/W (TSSOP)

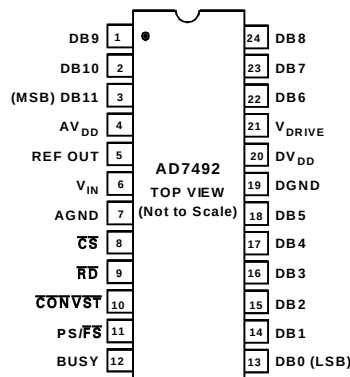
Lead Temperature, Soldering

Vapor Phase (60 secs)	+215°C
Infrared (15 secs)	+220°C

NOTES

¹Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions above those listed in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

²Transient currents of up to 100 mA will not cause SCR latch-up.

**ORDERING GUIDE**

Model	Temperature Range	Resolution (Bits)	Package Options ¹
AD7492ARU	-40°C to +85°C	12	RU-24
AD7492AR	-40°C to +85°C	12	R-24
EVAL-AD7492CB ²			Evaluation Board
EVAL-CONTROL BOARD ³			Controller Board
HSC-INTERFACE BOARD			Evaluation High Speed Interface

NOTES

¹R = SOIC; RU = TSSOP.

²This can be used as a stand-alone evaluation board or in conjunction with the EVAL-CONTROL BOARD for evaluation/demonstration purposes.

³This board is a complete unit allowing a PC to control and communicate with all Analog Devices evaluation boards ending in the CB designators.

CAUTION

ESD (electrostatic discharge) sensitive device. Electrostatic charges as high as 4000 V readily accumulate on the human body and test equipment and can discharge without detection. Although the AD7492 features proprietary ESD protection circuitry, permanent damage may occur on devices subjected to high energy electrostatic discharges. Therefore, proper ESD precautions are recommended to avoid performance degradation or loss of functionality.



PIN FUNCTION DESCRIPTION

Pin Mnemonic	Function
$\overline{CS}$	Chip Select. Active low logic input used in conjunction with $\overline{RD}$ to access the conversion result. The conversion result is placed on the data bus following the falling edge of both $\overline{CS}$ and $\overline{RD}$. $\overline{CS}$ and $\overline{RD}$ are both connected to the same AND gate on the input so the signals are interchangeable. $\overline{CS}$ can be hardwired permanently low.
$\overline{RD}$	Read Input. Logic Input used in conjunction with $\overline{CS}$ to access the conversion result. The conversion result is placed on the data bus following the falling edge of both $\overline{CS}$ and $\overline{RD}$. $\overline{CS}$ and $\overline{RD}$ are both connected to same AND gate on the input so the signals are interchangeable. $\overline{CS}$ and $\overline{RD}$ can be hardwired permanently low in which case, the data bus is always active and the result of the new conversion is clocked out slightly before to the BUSY line going low.
$\overline{CONVST}$	Conversion Start Input. Logic Input used to initiate conversion. The input track/hold amplifier goes from track mode to hold mode on the falling edge of $\overline{CONVST}$ and the conversion process is initiated at this point. The conversion input can be as narrow as 15 ns. If the $\overline{CONVST}$ input is kept low for the duration of conversion and is still low at the end of conversion, the part will automatically enter a sleep mode. The type of sleep mode is determined by the PS/ $\overline{FS}$ pin. If the part enters a sleep mode, the next rising edge of $\overline{CONVST}$ wakes up the part. Wake-up time for the part is typically 1 μ s.
PS/ $\overline{FS}$	Partial sleep/full sleep mode. This pin determines the type of sleep mode the part will enter if the $\overline{CONVST}$ pin is kept low for the duration of the conversion and is still low at the end of conversion. In partial sleep mode the internal reference circuit and oscillator circuit is not powered down and draws typically 200 μ V. In full sleep mode all of the analog circuitry is powered down and the current drawn is negligible.
BUSY	BUSY Output. Logic Output indicating the status of the conversion process. The BUSY signal goes high after the falling edge of $\overline{CONVST}$ and stays high for the duration of conversion. Once conversion is complete and the conversion result is in the output register, the BUSY line returns low. The track/hold returns to track mode just prior to the falling edge of BUSY and the acquisition time for the part begins when BUSY goes low. If the $\overline{CONVST}$ input is still low when BUSY goes low, the part automatically enters its sleep mode on the falling edge of BUSY.
REF OUT	Reference Out. The output voltage from this pin is 2.5 V $\pm$ 1%.
AV _{DD}	Analog Supply Voltage, +2.7 V to +5.25 V. This is the only supply voltage for all analog circuitry on the AD7492. The AV _{DD} and DV _{DD} voltages should ideally be at the same potential and must not be more than 0.3 V apart even on a transient basis. This supply should be decoupled to AGND.
DV _{DD}	Digital Supply Voltage, +2.7 V to +5.25 V. This is the supply voltage for all digital circuitry on the AD7492 apart from the output drivers and input circuitry. The DV _{DD} and AV _{DD} voltages should ideally be at the same potential and must not be more than 0.3 V apart even on a transient basis. This supply should be decoupled to DGND.
AGND	Analog Ground. Ground reference point for all analog circuitry on the AD7492. All analog input signals should be referred to this AGND voltage. The AGND and DGND voltages should ideally be at the same potential and must not be more than 0.3 V apart even on a transient basis.
DGND	Digital Ground. This is the ground reference point for all digital circuitry on the AD7492. The DGND and AGND voltages should ideally be at the same potential and must not be more than 0.3 V apart even on a transient basis.
V _{IN}	Analog Input. Single-ended analog input channel. The input range is 0 V to REFIN. The analog input presents a high dc input impedance.
V _{DRIVE}	Supply Voltage for the Output Drivers and Digital Input circuitry, +2.7 V to +5.25 V. This voltage determines the output high voltage for the data output pins and the trigger levels for the digital inputs. It allows the AV _{DD} and DV _{DD} to operate at 5 V (and maximize the dynamic performance of the ADC) while the digital input and output pins can interface to 3 V logic.
DB0–DB11	Data Bit 0 to DB11. Parallel digital outputs that provide the conversion result for the part. These are three-state outputs that are controlled by $\overline{CS}$ and $\overline{RD}$. The output high voltage level for these outputs is determined by the V _{DRIVE} input.

TERMINOLOGY**Integral Nonlinearity**

This is the maximum deviation from a straight line passing through the endpoints of the ADC transfer function. The endpoints of the transfer function are zero scale, a point 1/2 LSB below the first code transition, and full scale, a point 1/2 LSB above the last code transition.

Differential Nonlinearity

This is the difference between the measured and the ideal 1 LSB change between any two adjacent codes in the ADC.

Offset Error

This is the deviation of the first code transition (00 . . . 000) to (00 . . . 001) from the ideal, i.e., AGND + 1 LSB.

Gain Error

The last transition should occur at the analog value 1 1/2 LSB below the nominal full scale. The first transition is a 1/2 LSB above the low end of the scale (zero in the case of AD7492). The gain error is the deviation of the actual difference between the first and last code transitions from the ideal difference between the first and last code transitions with offset errors removed.

Track/Hold Acquisition Time

The track/hold amplifier returns into track mode after the end of conversion. Track/Hold acquisition time is the time required for the output of the track/hold amplifier to reach its final value, within ± 1 LSB, after the end of conversion.

Signal to (Noise + Distortion) Ratio

This is the measured ratio of signal to (noise + distortion) at the output of the A/D converter. The signal is the rms amplitude of the fundamental. Noise is the sum of all nonfundamental signals up to half the sampling frequency ($f_s/2$), excluding dc. The ratio is dependent on the number of quantization levels in the digitization process; the more levels, the smaller the quantization noise. The theoretical signal to (noise + distortion) ratio for an ideal N-bit converter with a sine wave input is given by:

$$\text{Signal to (Noise + Distortion)} = (6.02 N + 1.76) \text{ dB}$$

Thus for a 12-bit converter, this is 74 dB and for a 10-bit converter is 62 dB.

Total Harmonic Distortion

Total harmonic distortion (THD) is the ratio of the rms sum of harmonics to the fundamental. For the AD7492 it is defined as:

$$\text{THD (dB)} = 20 \log \frac{\sqrt{V_2^2 + V_3^2 + V_4^2 + V_5^2 + V_6^2}}{V_1}$$

where V_1 is the rms amplitude of the fundamental and V_2 , V_3 , V_4 , V_5 and V_6 are the rms amplitudes of the second through the sixth harmonics.

Peak Harmonic or Spurious Noise

Peak harmonic or spurious noise is defined as the ratio of the rms value of the next largest component in the ADC output spectrum (up to $f_s/2$ and excluding dc) to the rms value of the fundamental. Normally, the value of this specification is determined by the largest harmonic in the spectrum, but for ADCs where the harmonics are buried in the noise floor, it will be a noise peak.

Intermodulation Distortion

With inputs consisting of sine waves at two frequencies, f_a and f_b , any active device with nonlinearities will create distortion products at sum and difference frequencies of $m f_a \pm n f_b$ where $m, n = 0, 1, 2, 3$, etc. Intermodulation distortion terms are those for which neither m nor n is equal to zero. For example, the second order terms include $(f_a + f_b)$ and $(f_a - f_b)$, while the third order terms include $(2f_a + f_b)$, $(2f_a - f_b)$, $(f_a + 2f_b)$ and $(f_a - 2f_b)$.

The AD7492 is tested using the CCIF standard where two input frequencies near the top end of the input bandwidth are used. In this case, the second order terms are usually distanced in frequency from the original sine waves while the third order terms are usually at a frequency close to the input frequencies. As a result, the second and third order terms are specified separately. The calculation of the intermodulation distortion is as per the THD specification where it is the ratio of the rms sum of the individual distortion products to the rms amplitude of the sum of the fundamentals expressed in dBs.

Aperture Delay

In a sample/hold, the time required after the hold command for the switch to open fully is the aperture delay. The sample is, in effect, delayed by this interval, and the hold command would have to be advanced by this amount for precise timing.

Aperture Jitter

Aperture jitter is the range of variation in the aperture delay. In other words, it is the uncertainty about when the sample is taken. Jitter is the result of noise which modulates the phase of the hold command. This specification establishes the ultimate timing error, hence the maximum sampling frequency for a given resolution. This error will increase as the input dV/dt increases.

CIRCUIT DESCRIPTION**CONVERTER OPERATION**

The AD7492 is a 12-bit successive approximation analog-to-digital converter based around a capacitive DAC. The AD7492 can convert analog input signals in the range 0 V to V_{REF} . Figure 2 shows a very simplified schematic of the ADC. The Control Logic, SAR and the Capacitive DAC are used to add and subtract fixed amounts of charge from the sampling capacitor to bring the comparator back into a balanced condition.

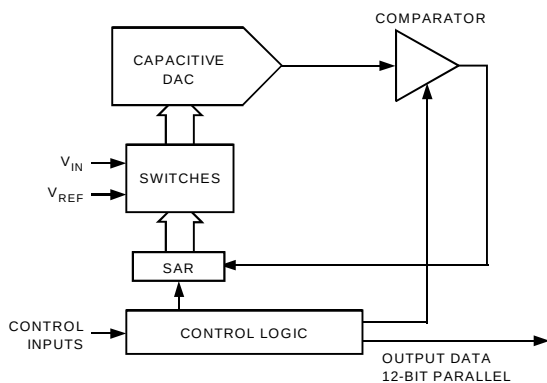


Figure 2. Simplified Block Diagram of AD7492

Figure 3 shows the ADC during its acquisition phase. SW2 is closed and SW1 is in Position A. The comparator is held in a balanced condition and the sampling capacitor acquires the signal on V_{IN} .

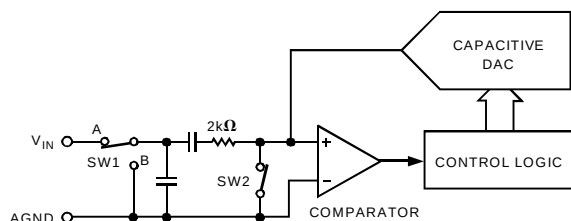


Figure 3. ADC Acquisition Phase

Figure 4 shows the ADC during conversion. When conversion starts SW2 will open and SW1 will move to position B, causing the comparator to become unbalanced. The ADC then runs through its successive approximation routine and brings the comparator back into a balanced condition. When the comparator is rebalanced, the conversion result is available in the SAR register.

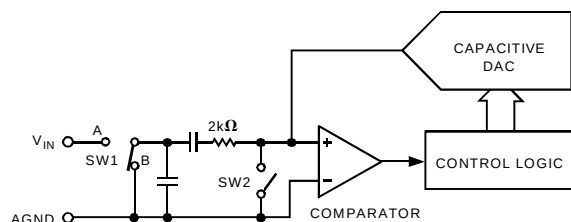
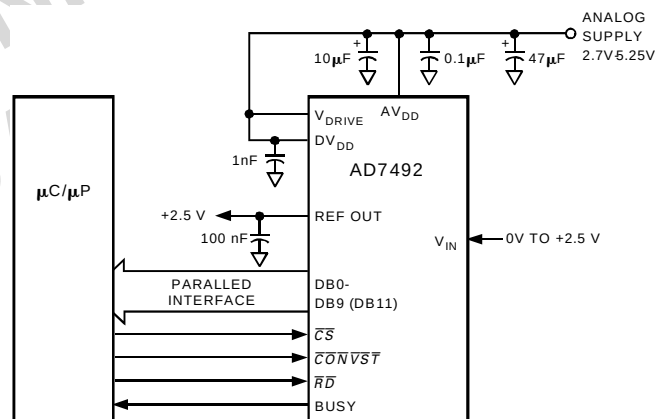


Figure 4. ADC Conversion Phase

TYPICAL CONNECTION DIAGRAM

Figure 5 shows a typical connection diagram for the AD7492. Conversion is initiated by a falling edge on $\overline{CONVST}$. Once $\overline{CONVST}$ goes low the BUSY signal goes high, and at the end of conversion the falling edge of BUSY is used to activate an Interrupt Service Routine. The $\overline{CS}$ and $\overline{RD}$ lines are then activated in parallel to read the 12-data bits. The internal bandgap reference voltage is 2.5 V providing an analog input range of 0 V to 2.5 V, making the AD7492 a unipolar A/D. A capacitor with a minimum capacitance of 100 nF is needed at the output of the REF OUT pin as it stabilizes the internal reference value. It is recommended to perform a dummy conversion after power-up as the first conversion result could be incorrect. This also ensures that the part is in the correct mode of operation. The $\overline{CONVST}$ pin should not be floating when power is applied as a rising edge on $\overline{CONVST}$ might not wake up the part.

In Figure 5 the V_{DRIVE} pin is tied to DV_{DD} , which results in logic output voltage values being either 0 V or DV_{DD} . The voltage applied to V_{DRIVE} controls the voltage value of the output logic signals and the input logic signals. For example, if DV_{DD} is supplied by a 5 V supply and V_{DRIVE} by a 3 V supply, the logic output voltage levels would be either 0 V or 3 V. This feature allows the AD7492 to interface to 3



V parts while still enabling the A/D to process signals at 5 V supply.

Figure 5. Typical Connection Diagram

ADC TRANSFER FUNCTION

The output coding of the AD7492 is straight binary. The designed code transitions occur at successive integer LSB values (i.e., 1 LSB, 2 LSB, etc.). The LSB size is $= (\text{REF IN})/4096$ for the AD7492. The ideal transfer characteristic for the AD7492 is shown in Figure 6.

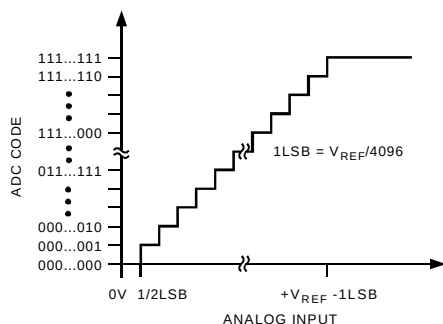


Figure 6. Transfer Characteristic for 12 Bits

AC ACQUISITION TIME

In ac applications it is recommended to always buffer analog input signals. The source impedance of the drive circuitry must be kept as low as possible to minimize the acquisition time of the ADC. Large values of impedance at the V_{IN} pin of the ADC will cause the THD to degrade at high input frequencies.

INPUT BUFFERS	AD7492 DYNAMIC PERFORMANCE SPECIFICATIONS		TYPICAL AMPLIFIER CURRENT CONSUMPTION
	SNR 500kHz	THD 500kHz	
AD8047	70	78	5.8mA
AD9631	69.5	80	17mA
AD8051	68.6	78	4.4mA
AD797	70	84	8.2mA

DC Acquisition Time

The ADC starts a new acquisition phase at the end of a conversion and ends it on the falling edge of the CONVST signal. At the end of conversion there is a settling time associated with the sampling circuit. This settling time lasts approximately 140 ns. The analog signal on V_{IN} is also being acquired during this settling time; therefore, the minimum acquisition time needed is approximately 140 ns.

Figure 8 shows the equivalent charging circuit for the sampling capacitor when the ADC is in its acquisition phase. $R3$ represents the source impedance of a buffer amplifier or resistive network, $R1$ is an internal switch resistance, $R2$ is for bandwidth control and $C1$ is the sampling capacitor. $C2$ is back-plate capacitance and switch parasitic capacitance.

During the acquisition phase the sampling capacitor must be charged to within 1 LSB of its final value.

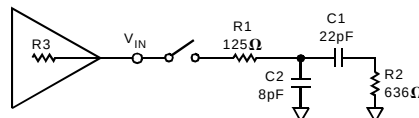


Figure 8. Equivalent Sampling Circuit

ANALOG INPUT

Figure 9 shows the equivalent circuit of the analog input structure of the AD7492. The two diodes, $D1$ and $D2$, provide ESD protection for the analog inputs. The capacitor $C3$ is typically about 4 pF and can be primarily attributed to pin capacitance. The resistor $R1$ is an internal switch resistance. This resistor is typically about 125 ohms. The capacitor $C1$ is the sampling capacitor while $R2$ is used for bandwidth control.

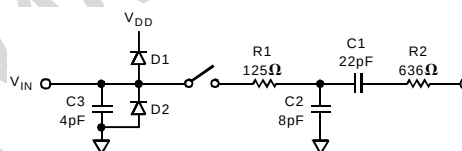


Figure 9. Equivalent Analog Input Circuit

PARALLEL INTERFACE

The parallel interface of the AD7492 is 12-bits wide. The output data buffers are activated when both $\overline{CS}$ and $\overline{RD}$ are logic low. At this point the contents of the data register are placed onto the data bus. Figure 10 shows the timing diagram for the parallel port.

Figure 11 shows the timing diagram for the parallel port when $\overline{CS}$ and $\overline{RD}$ are tied permanently low. In this setup, once the $BUSY$ line goes from high to low the conversion process is

completed. The data is available on the output bus slightly before the falling edge of $BUSY$.

It is important to point out that data bus cannot change state while the A/D is doing a conversion as this would have a detrimental effect on the conversion in progress. The data out lines will go three-state again when either the $\overline{RD}$ or $\overline{CS}$ line goes high. Thus the $\overline{CS}$ can be tied low permanently, leaving the $\overline{RD}$ line to control conversion result access. Please reference the V_{DRIVE} section for output voltage levels.

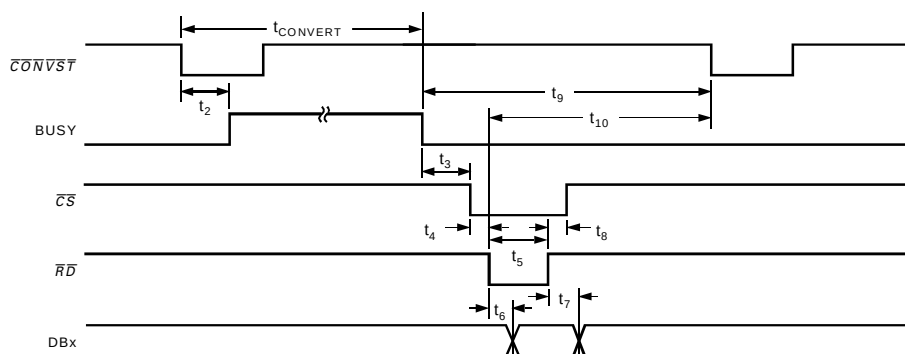


Figure 10. Parallel Port Timing

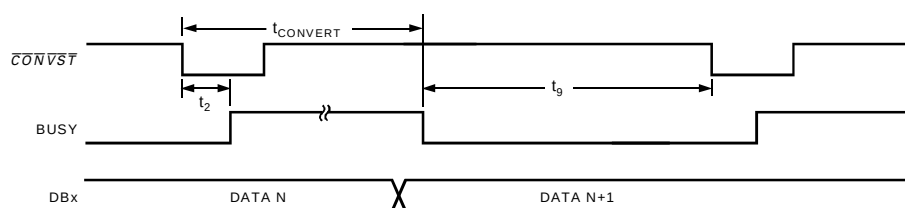


Figure 11. Parallel Port Timing with CS and RD Tied Low

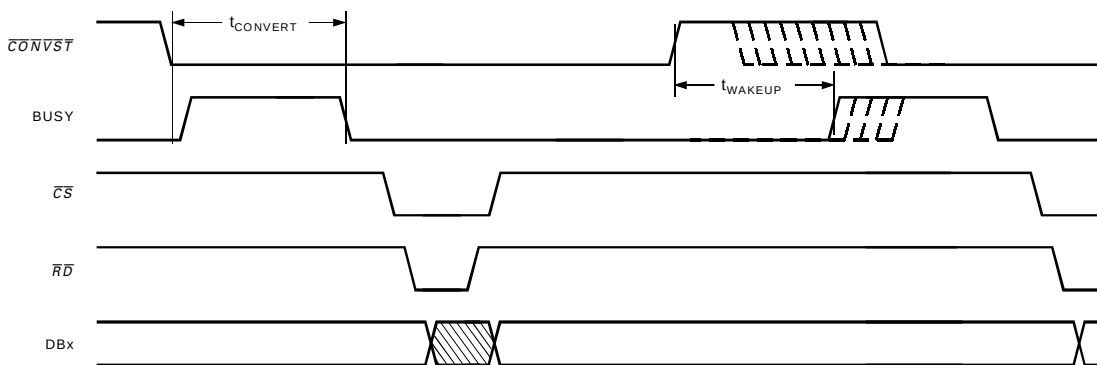


Figure 13. Mode 2 Operation

OPERATING MODES

The AD7492 has two possible modes of operation depending on the state of the $\overline{\text{CONVST}}$ pulse at the end of a conversion, Mode 1 and Mode 2.

Mode 1 (High Speed Sampling)

In this mode of operation the $\overline{\text{CONVST}}$ pulse is brought high before the end of conversion i.e., before the BUSY goes low (see Figure 10). If the $\overline{\text{CONVST}}$ pin is brought from high to low while BUSY is high, the conversion is restarted. When operating in this mode a new conversion should not be initiated until 135 ns after BUSY goes low. This acquisition time allows the track/hold circuit to accurately acquire the input signal. As mentioned earlier, a read should not be done during a conversion. This mode facilitates the fastest throughput times for the AD7492.

Mode 2 (Partial or Full Sleep Mode)

Figure 13 shows AD7492 in Mode 2 operation where the ADC goes into either partial or full sleep mode after conversion. The $\overline{\text{CONVST}}$ line is brought low to initiate a conversion and remains low until after the end of conversion. If $\overline{\text{CONVST}}$ goes high and low again while BUSY is high, the conversion is restarted. Once the BUSY line goes from a high to a low, the $\overline{\text{CONVST}}$ line has its status checked and, if low, the part enters a sleep mode. The type of sleep mode the AD7492 enters depends on what ever way the $\text{PS}/\overline{\text{FS}}$ pin is hardwired. If the $\text{PS}/\overline{\text{FS}}$ pin is tied high then the AD7492 will enter partial sleep mode. If the $\text{PS}/\overline{\text{FS}}$ pin is tied low the AD7492 will enter full sleep mode.

The device wakes up again on the rising edge of the $\overline{\text{CONVST}}$ signal. From partial sleep the wake-up time is typically 1 μs after the rising edge of $\overline{\text{CONVST}}$ and before the BUSY line can go high to indicate start of conversion. From full sleep this wake-up time is typically 500 μs . BUSY will only go high once $\overline{\text{CONVST}}$ goes low. The $\overline{\text{CONVST}}$ line can go from a high to a low during the wake-up time, but the conversion will still not be initiated until after the wake-up time. Superior power performance can be achieved in these modes of operation by waking up the AD7492 only to carry out a conversion. The optimum power performance is obtained when using full sleep mode as the ADC comparator, Reference buffer and Reference

circuit is powered down. While in partial sleep mode, only the ADC comparator is powered down and the reference buffer is put into a low power mode. The 100 nF capacitor on the REF OUT pin is kept charged up by the reference buffer in partial sleep mode while in full sleep mode this capacitor slowly discharges. This explains why the wake-up time is shorter in partial sleep mode. In both sleep modes the clock oscillator circuit is powered down.

V_{DRIVE}

The V_{DRIVE} pin is used as the voltage supply to the output drivers and is a separate supply from AV_{DD} and DV_{DD} . The purpose of using a separate supply for the output drivers is that the user can vary the output high voltage, V_{OH} , from the V_{DD} supply to the AD7492. For example, if AV_{DD} and DV_{DD} is using a 5 V supply, the V_{DRIVE} pin can be powered from a 3 V supply. The ADC has better dynamic performance at 5 V than at 3 V, so operating the part at 5 V, while still being able to interface to 3 V parts, pushes the AD7492 to the top bracket of high performance 12-bit A/Ds. Of course, the ADC can have its V_{DRIVE} and DV_{DD} pins connected together and be powered from a 3 V or 5 V supply.

All outputs are powered from V_{DRIVE} . These are all the data out pins and the BUSY pin.

POWER-UP

It is recommended that the user performs a dummy conversion after power-up, as the first conversion result could be incorrect. This also ensures that the parts is in the correct mode of operation. The recommended power-up sequence is as follows:

- 1 > GND
- 2 > V_{DD}
- 3 > V_{DRIVE}
- 4 > Digital Inputs
- 5 > V_{IN}

Power vs. Throughput

The two modes of operation for the AD7492 will produce different power versus throughput performances, Mode 1 and Mode 2; see Operating Modes section of the data sheet for more detailed descriptions of these modes. Mode 2 is the Sleep Mode (Partial/Full) of the part and it achieves the optimum power performance.

Mode 1

Figure 14 shows the AD7492 conversion sequence in Mode 1 using a throughput rate of 500 kSPS. At 5 V supply the current consumption for the part when converting is 2 mA and the quiescent current is 650 μ A. The conversion time of 810 ns contributes 4.05 mW to the overall power dissipation in the following way:

$$(810 \text{ ns}/2 \mu\text{s}) \times (5 \times 2 \text{ mA}) = 4.05 \text{ mW}$$

The contribution to the total power dissipated by the remaining 1.19 μ s of the cycle is 1.93 mW.

$$(1.19 \mu\text{s}/2 \mu\text{s}) \times (5 \times 650 \mu\text{A}) = 1.93 \text{ mW}$$

Thus the power dissipated during each cycle is:

$$4.05 \text{ mW} + 1.93 \text{ mW} = 5.98 \text{ mW}$$

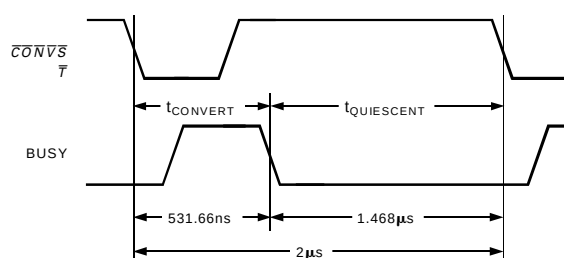


Figure 14. Mode 1 Power Dissipation

Mode 2 (Full Sleep Mode)

Figure 15 shows the AD7492 conversion sequence in Mode 2, Full Sleep mode, using a throughput rate of approximately 1.18 kSPS. At 5 V supply the current consumption for the part when converting is 2 mA, while the full sleep current is 1 μ A max. The power dissipated during this power-down is negligible and is thus not worth considering in the total power figure. During the wake-up phase, the AD7492 will draw 650 μ A. Overall power dissipated is:

$$(810 \text{ ns}/550 \mu\text{s}) \times (5 \times 2 \text{ mA}) + (500 \mu\text{s}/550 \mu\text{s}) \times (5 \times 650 \mu\text{A}) = 2.97 \text{ mW}$$

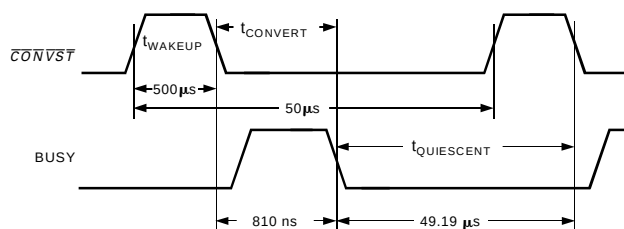


Figure 15. Full Sleep Power Dissipation

Mode 2 (Partial Sleep Mode)

Figure 16 shows the AD7492 conversion sequence in Mode 2, Partial Sleep mode, using a throughput rate of 500 kSPS. At 5 V supply the current consumption for the part when converting is 2 mA, while the partial sleep current is 190 μ A max. During the wake-up phase, the AD7492 will draw 650 μ A. Power dissipated during wake-up and conversion is :

$$(810 \text{ ns}/2 \mu\text{s}) \times (5 \times 2 \text{ mA}) + (1 \mu\text{s}/2 \mu\text{s}) \times (5 \times 650 \mu\text{A}) = 5.675 \text{ mW}$$

Power dissipated during power-down is :

$$(190 \text{ ns}/2 \mu\text{s}) \times (5 \times 190 \mu\text{A}) = 90.25 \mu\text{W}$$

Overall power dissipated is :

$$5.675 \text{ mW} + 90.25 \mu\text{W} = 5.765 \text{ mW}$$

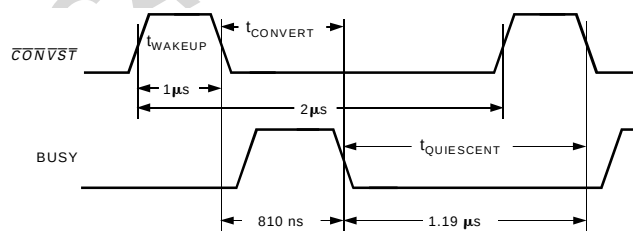


Figure 16. Partial Sleep Power Dissipation

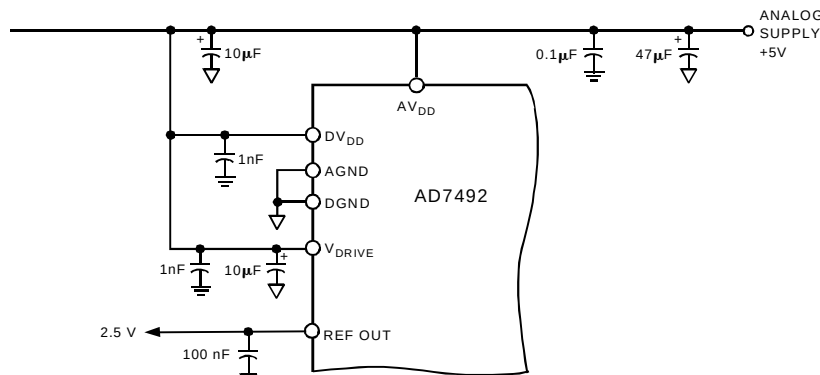


Figure 25. Typical Decoupling Circuit

GROUNDING AND LAYOUT

The analog and digital power supplies are independent and separately pinned out to minimize coupling between analog and digital sections within the device. To complement the excellent noise performance of the AD7492 it is imperative that care be given to the PCB layout. Figure 25 shows a recommended connection diagram for the AD7492.

All of the AD7492 ground pins should be soldered directly to a ground plane to minimize series inductance. The AV_{DD} , DV_{DD} and V_{DRIVE} pins should be decoupled to both the analog and digital ground planes. The REF OUT pin should be decoupled to the analog ground plane with a minimum capacitor value of 100 nF. This capacitor helps to stabilize the internal reference circuit. The large value capacitors will decouple low frequency noise to analog ground, the small value capacitors will decouple high frequency noise to digital ground. All digital circuitry power pins should be decoupled to the digital ground plane. The use of ground planes can physically separate sensitive analog components from the noisy digital system. The two ground planes should be joined in *only* one place and should not overlap so as to minimize capacitive coupling between them. If the AD7492 is in a system where multiple devices require AGND to DGND connections, the connection should still be made at one point only, a star ground point, which should be established as close as possible to the AD7492.

Noise can be minimized by applying some simple rules to the PCB layout: analog signals should be kept away from digital signals; fast switching signals like clocks should be shielded with digital ground to avoid radiating noise to other sections of the board and clock signals should never be run near the analog inputs; avoid running digital lines under the device as these will couple noise onto the die; the power supply lines to the AD7492 should use as large a trace as possible to provide a low impedance path and reduce the effects of glitches on the power supply line; avoid crossover of digital and analog signals and place traces that are on opposite sides of the board at right angles to each other.

Noise to the analog power line can be further reduced by use of multiple decoupling capacitors as shown in Figure 25. Decoupling capacitors should be placed directly at the power inlet to the PCB and also as close as possible to the power pins of the AD7492. The same decoupling method should be used on other ICs on the PCB, with the capacitor leads as short as possible to minimize lead inductance.

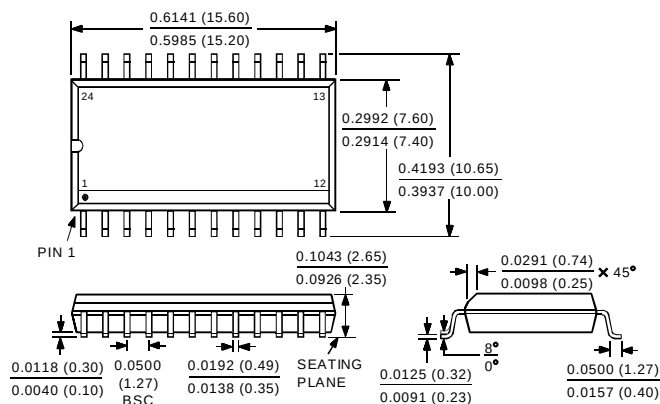
POWER SUPPLIES

Separate power supplies for AV_{DD} and DV_{DD} are desirable but if necessary DV_{DD} may share its power connection to AV_{DD} . The digital supply (DV_{DD}) must not exceed the analog supply (AV_{DD}) by more than 0.3 V in normal operation.

OUTLINE DIMENSIONS

Dimensions shown in inches and (mm).

24-Lead SOIC (R-24)



24-Lead TSSOP (RU-24)

